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## Diverse Electron-induced Optical Emissions from Space Observatory Materials at Low Temperatures

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Dennison, JR; Evans Jensen, Amberly; Wilson, Greg; Dekany, Justin; Bowers, Charles W.; and Meloy, Robert, "Diverse Electron-induced Optical Emissions from Space Observatory Materials at Low Temperatures" (2013). SPIE Optics and Photonics Conference. *Presentations*. Paper 24.  
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*San Diego, CA*  
*August 25-29, 2013*

# ***Diverse Electron-induced Optical Emissions from Space Observatory Materials at Low Temperatures***

**JR Dennison<sup>a</sup>, Amberly Evans Jensen<sup>a</sup>, Gregory Wilson<sup>a</sup>, Justin Dekany<sup>a</sup>, Charles W. Bowers<sup>b</sup>, and Robert Meloy<sup>c</sup>**

<sup>a</sup> ***Materials Physics Group, Physics Department, Utah State University***

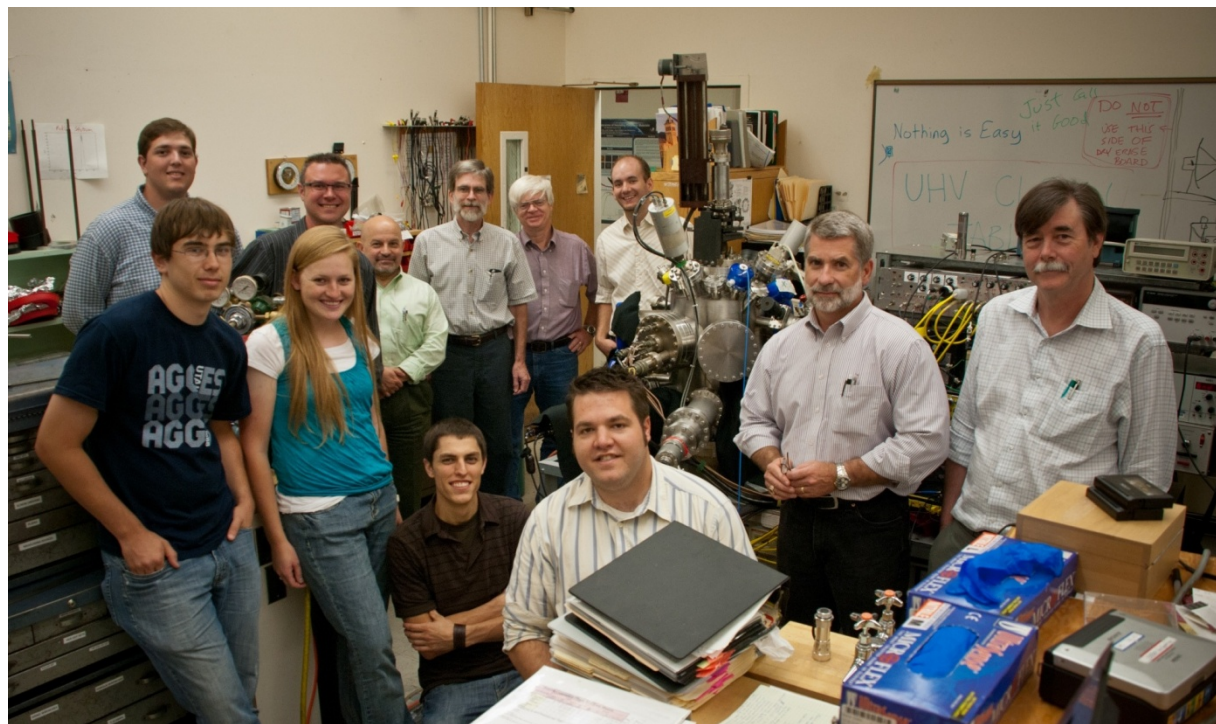
<sup>b</sup> ***NASA Goddard Space Flight Center***

<sup>c</sup> ***MEI Technologies, Inc.,***

# Acknowledgements

## Support and Collaborations

\*Work is supported by NASA projects through GSFC and additional support by the Air Force Research Laboratory (AFRL), the National Research Council Fellowship (Dennison), a NASA NSTR Fellowship (Jensen), and the USU Research Office (Jensen, Wilson, Dekany).



## USU Materials Physics Group NASA Goddard Space Flight Center

Supported by the NASA Space Environments & Effects Program and various other sources



# Central Question of This Presentation

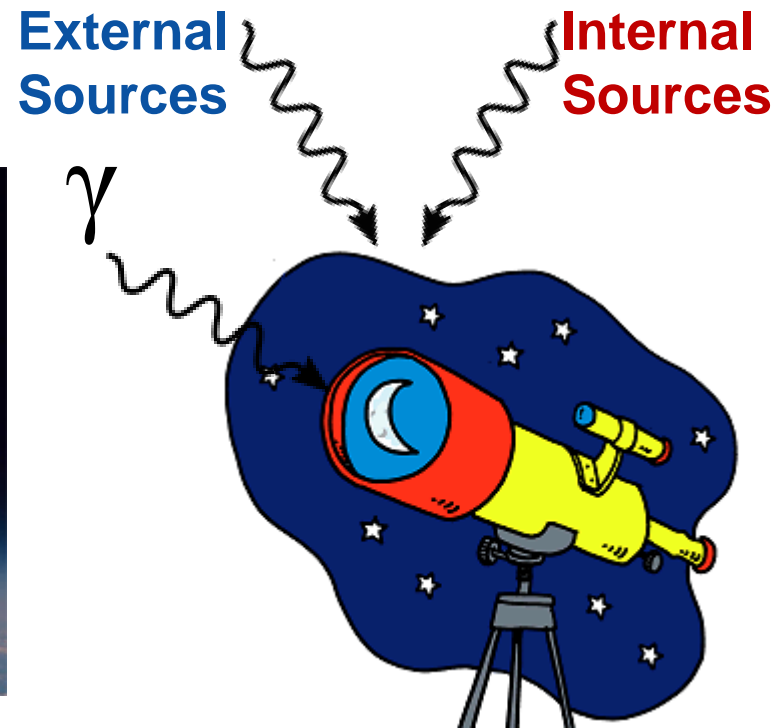
**Can interactions of the space environment electron flux with observatory materials make significant contributions to the stray light background and adversely affect the performance of space-based observatories?**

$e^-$



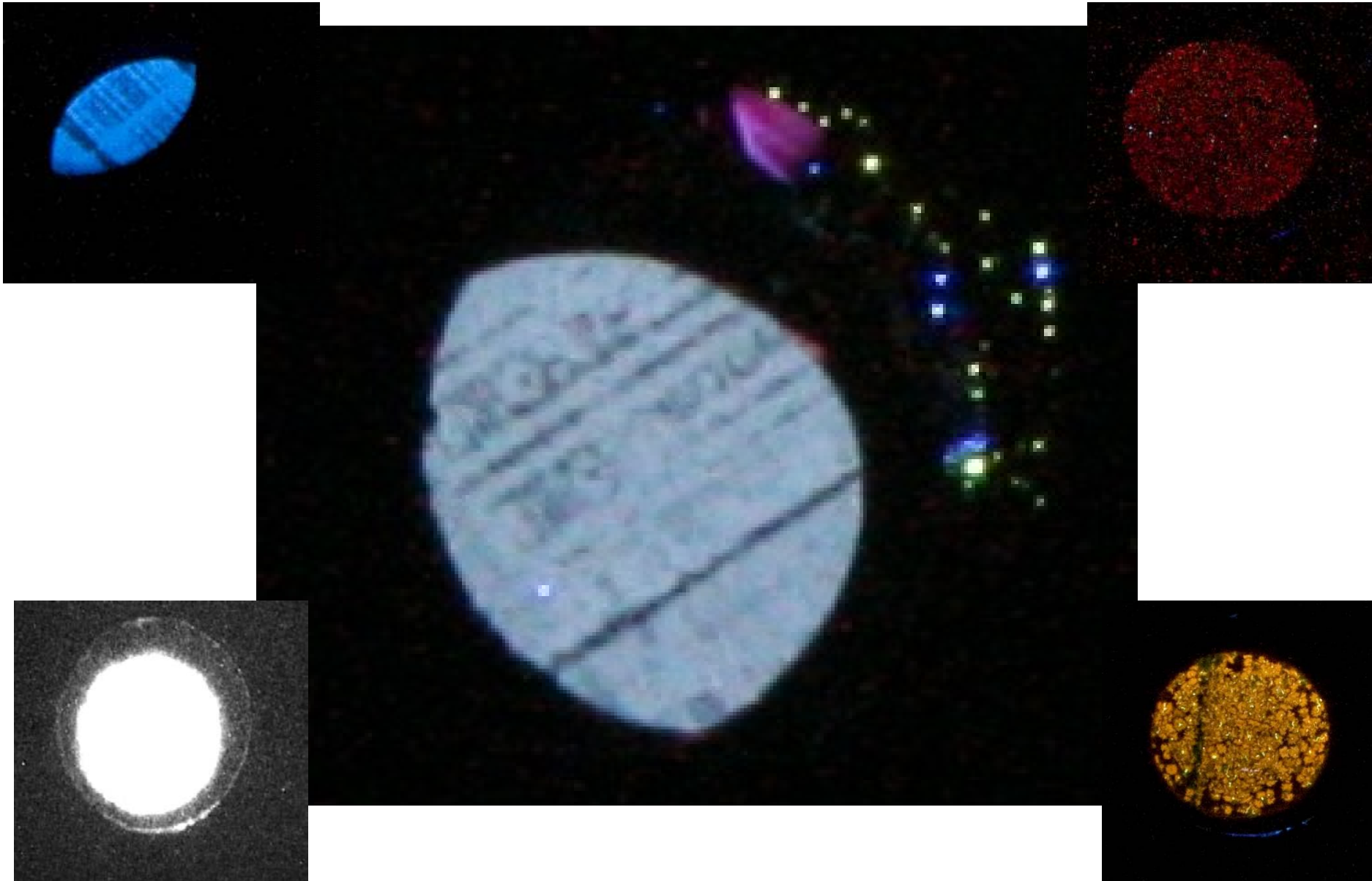
Space Environment  
Fluxes

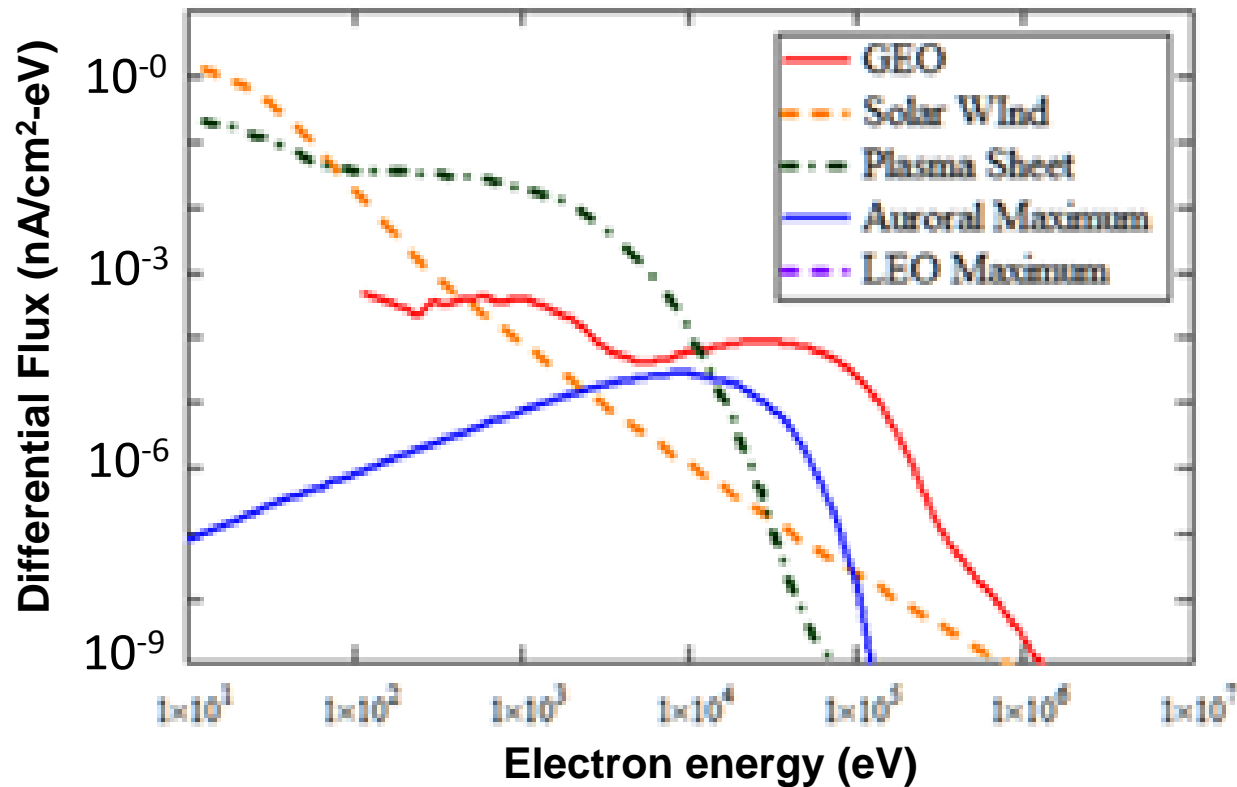
Space-based Observatory  
Moving through Space



Stray Light  
Background

# The short answer is **YES!**





## Typical “Worst Case” Environments have:

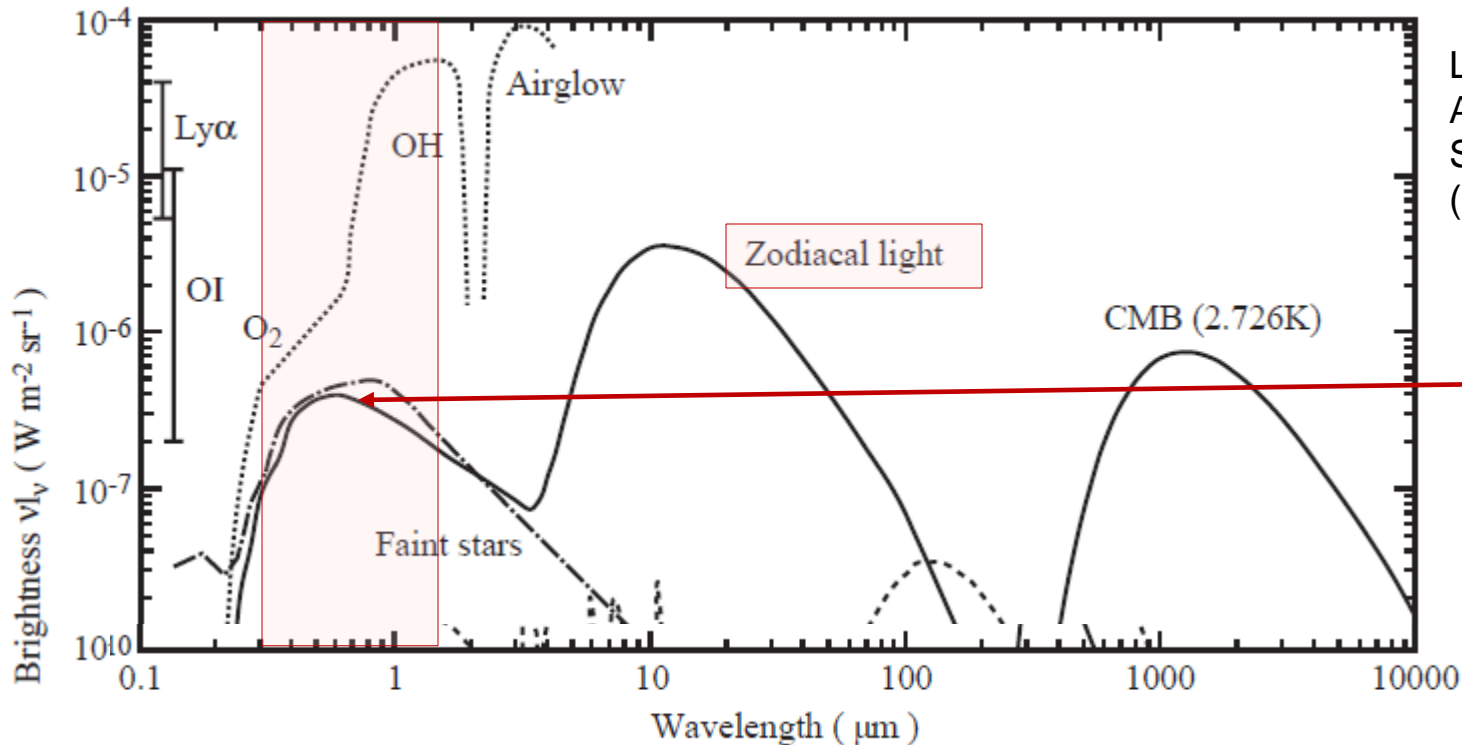
- Peak fluxes:  $<10 \text{ nA/cm}^2$
- Energy range:  $<1 \text{ keV to } > 1 \text{ MeV}$
- Peak power density:  $<10 \text{ } \mu\text{W/cm}^2$

## Flux exposures vary significantly with:

- Time
- Space weather
- Mission orbit
- Satellite geometry and design



# Comparison with External Sources of Stray Light



Leinert, *et al.*,  
Astron. Astrophys.  
Suppl. Ser. 127, 1-99  
(1998).

**Zodiacal  
Background  
Spectral  
Radiance**

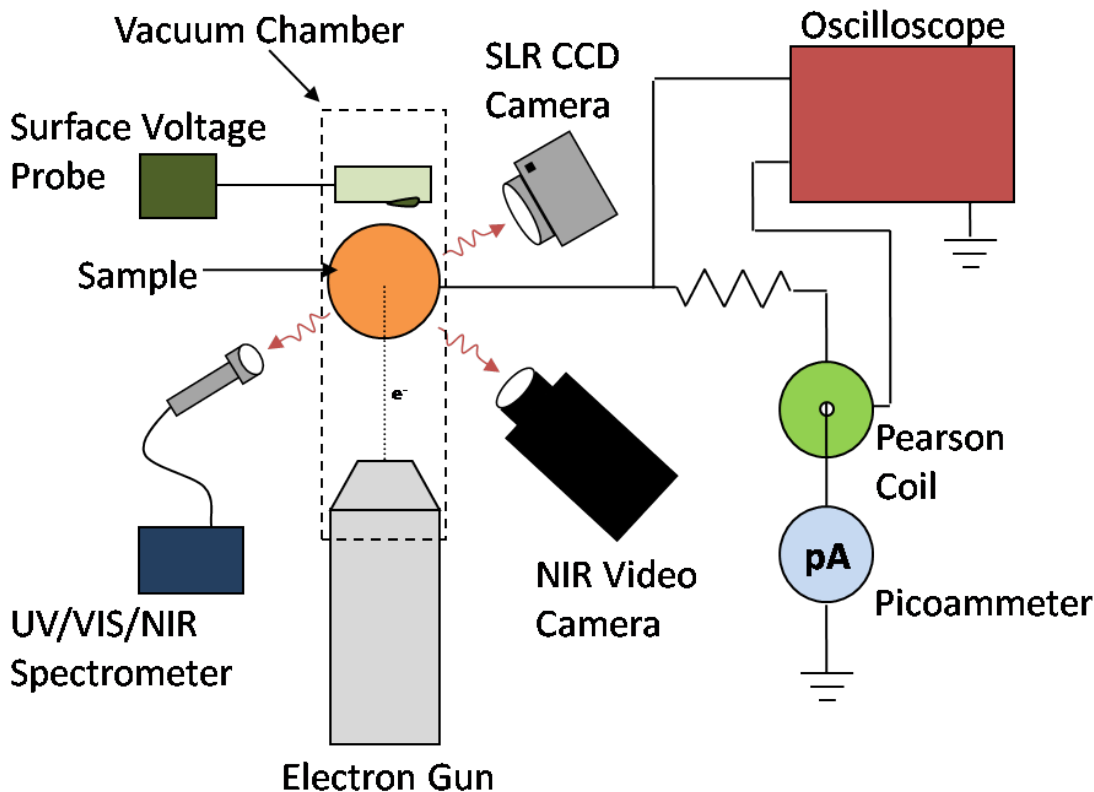
**$\sim 1-7 \cdot 10^{-14}$   
[ $W-(cm-nm-sr)^{-1}$ ]**

## External Sources

- Atmospheric air glow
- Zodiacal light (dust scatter & thermal emission)
- Integrated diffuse starlight
- Extragalactic diffuse light
- Cosmic microwave background

## Internal Sources

- Thermal emission from telescope
- Electron-induced emissions



## System Specifications

- **Samples:** 1-5 cm<sup>2</sup>, grounded holder
- **Vacuum:** <math>10^{-7}</math> Torr
- **Temperature:** <math>40</math> K to <math>350</math> K
- **e-Beam:** <math>20</math> eV to 30 keV  
<math>10</math> pA/cm<sup>2</sup> to >10  $\mu$ A/cm<sup>2</sup>

## Photon and Electron Detection

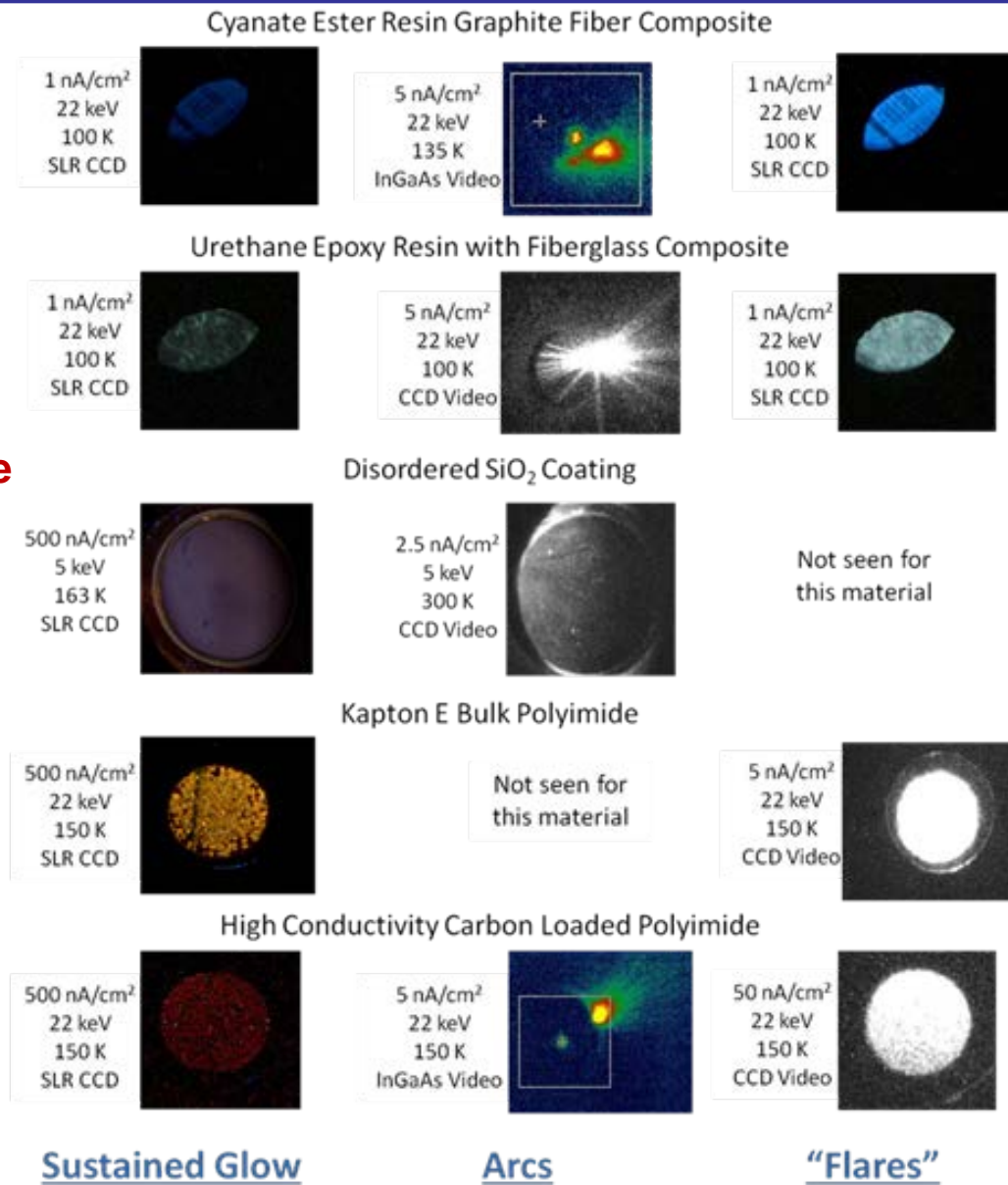
- 4 cameras with absolute calibration
- <math>2</math> fW/cm<sup>2</sup>-nm-sr sensitivity
- ~200 nm to ~1900 nm  $\lambda$  range
- 0.03 Hz to 60 Hz sampling rate
- UV/Vis and NIR spectrometers
- Currents to <math>0.1</math> pA at up to 2 GHz



# Examples of Electron-Induced Optical Emission

## Electron-Induced Emissions Observed

- Sustained Cathodoluminescence
- Short duration arcing
- Intermediate duration “Flares”



Sustained Glow

Arcs

“Flares”

## Glowing Dielectric Materials

### Polymers

- Polyimide (Kapton™ HN and E)
- Urethane Epoxy
- Amine Epoxy

### Glasses

- Disordered SiO<sub>2</sub>

### Composites

- Carbon-loaded polyimide
- Cyanate ester/graphite fiber composite
- Urethane Epoxy/Carbon fiber composite
- Epoxy/Fiberglass composite

### Multilayer Dielectric/Conductor Composites

# Diversity of Emission Phenomena in Time Domain

## Surface Glow

- Relatively low intensity
- Glows when e-beam on
- Present over full surface
- May decay slowly with time
- Dependant on space charge

## Edge Glow

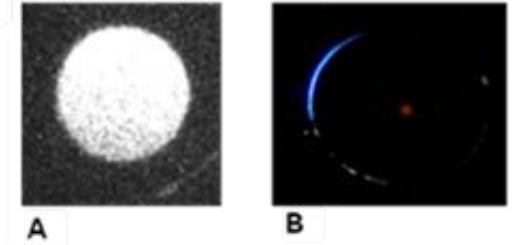
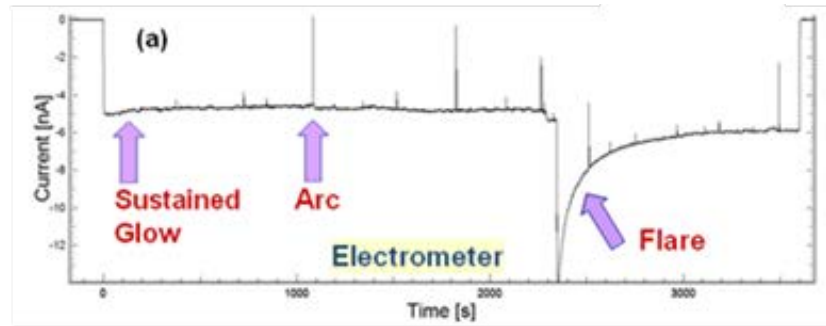
- Similar to surface glow
- Less intense than surface glow
- Only at sample edges

## Arcs

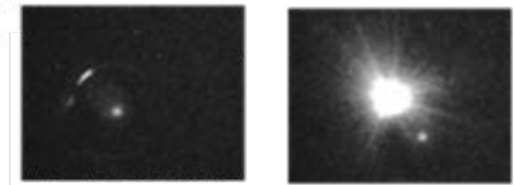
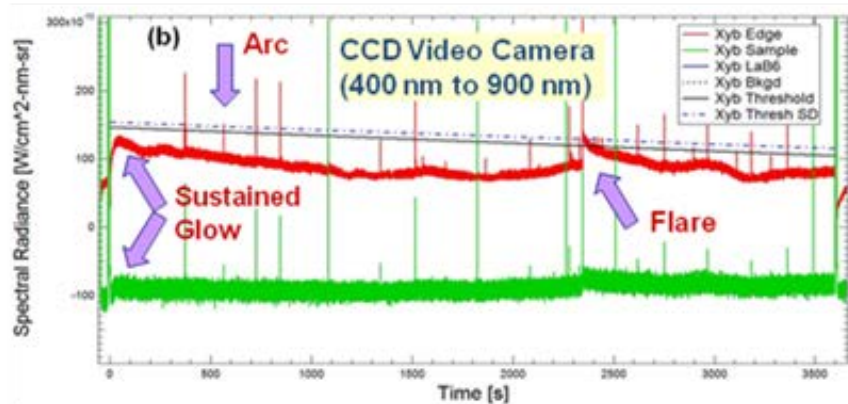
- Coincident with electric discharge
- Relatively very high intensity
- 10-1000X glow intensity
- Abrupt onset, <100 ns
- Very short duration, <1 us to 1 s

## "Flares"

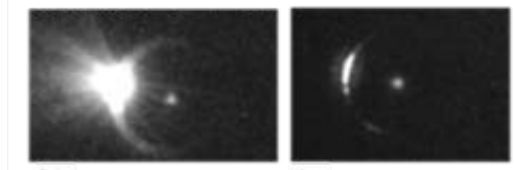
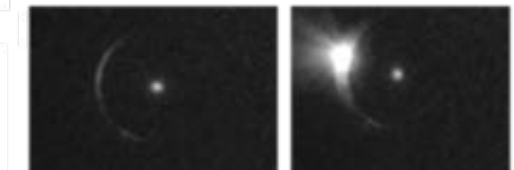
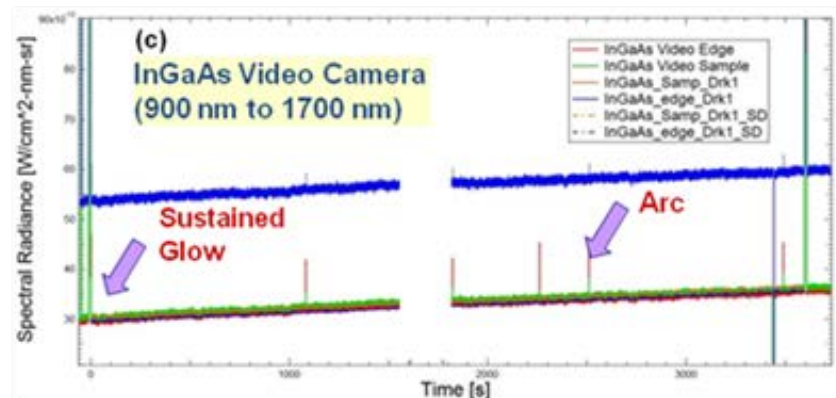
- 2-20x glow intensity
- Present over full surface
- Abrupt onset
- 1-10 min decay times



(d)



(e)

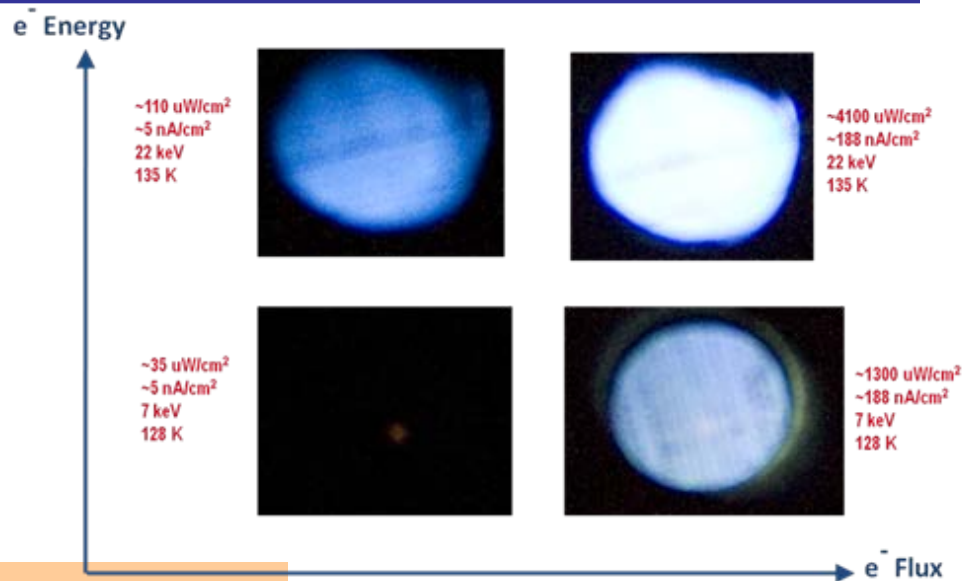


(f)

Carbon-loaded Polyimide 22 keV, 5 nA/cm<sup>2</sup>, 110 uW/cm<sup>2</sup>, 135 K

# Dependencies of Cathodoluminescence Intensity

- Linearly increases with deposited current, energy and power
- Linearly increases with decreasing T
- Emissions in VIS/NIR, peaked in VIS
- Saturates at high dose rates (above space conditions)
- Plateaus and decreases below ~100 K
- Decreases with increasing energy for penetrating radiation



Luminescence power  $P_\gamma$  is:

$$P_\gamma(J_b, E_b, T, \lambda) \propto \frac{\dot{D}(J_b, E_b)}{\dot{D} + \dot{D}_{sat}} \left\{ \left[ e^{-(\epsilon_{ST}/k_B T)} \right] \left[ 1 - e^{-(\epsilon_{ST}/k_B T)} \right] \right\},$$

where dose rate  $\dot{D}$  (absorbed power per unit mass) is:

$$\dot{D}(J_b, E_b) = \frac{E_b J_b [1 - \eta(E_b)]}{q_e \rho_m} \times \begin{cases} [1/L] & ; R(E_b) < L \\ [1/R(E_b)] & ; R(E_b) > L \end{cases}$$

$E_b$ , incident beam energy

$J_b$ , incident e-Beam current density

$T$ , temperature

$\lambda$ , photon wavelength

$\epsilon_{ST}$ , shallow trap energy

$q_e$ , electron charge

$\rho_m$ , mass density

$R(E_b)$ , electron range

$L$ , sample thickness

$\dot{D}_{sat}$ , saturation dose rate

## Approximate Relative Sp. Rad. (X Zodi Background)

### Polymers

- Polyimide (Kapton™ HN and E) X0.05
- Urethane Epoxy X50
- Amine Epoxy X20

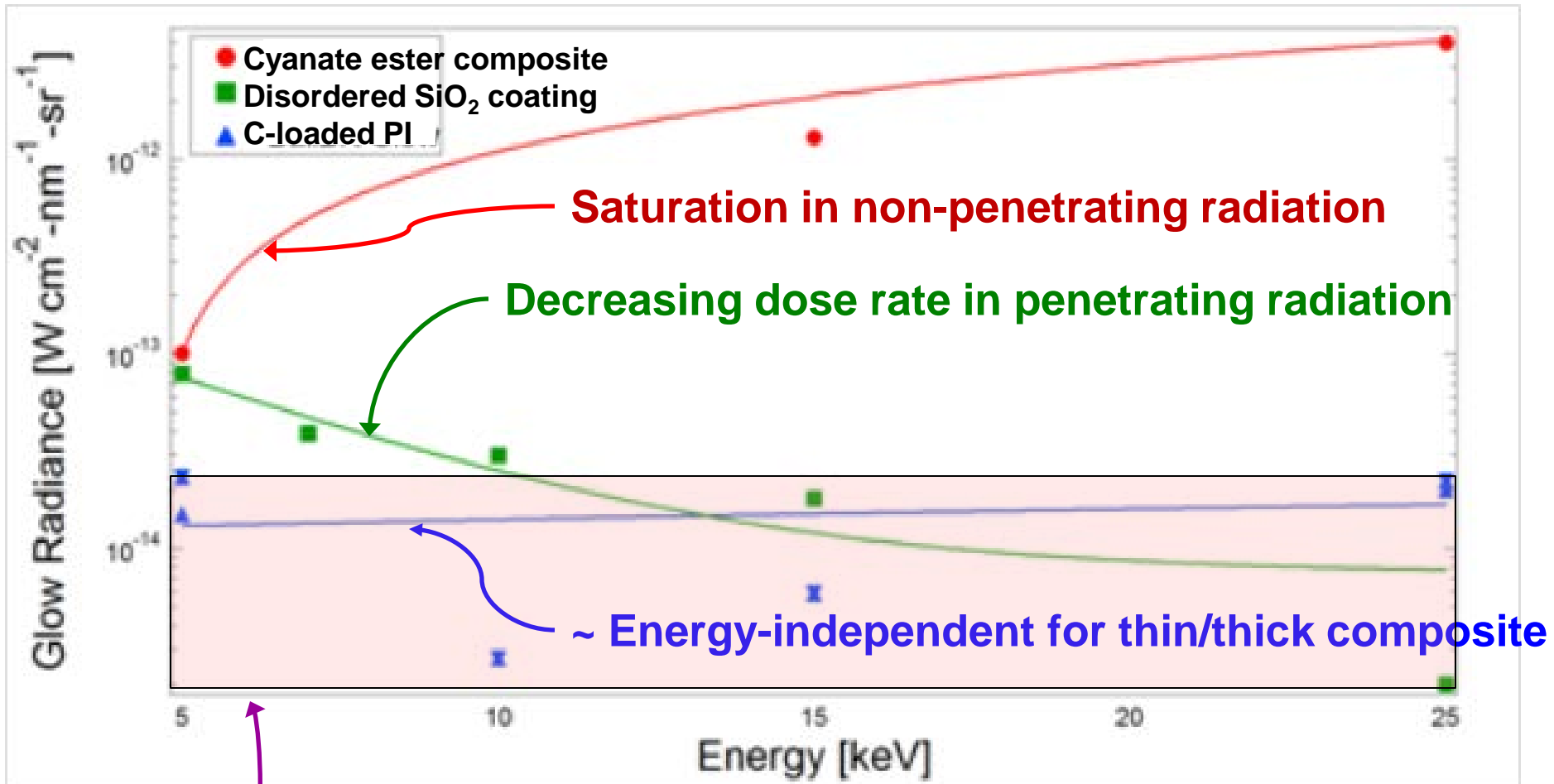
### Glasses

- Disordered SiO<sub>2</sub> X1

### Composites

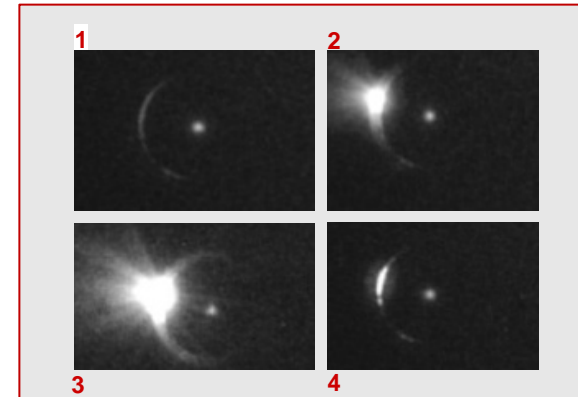
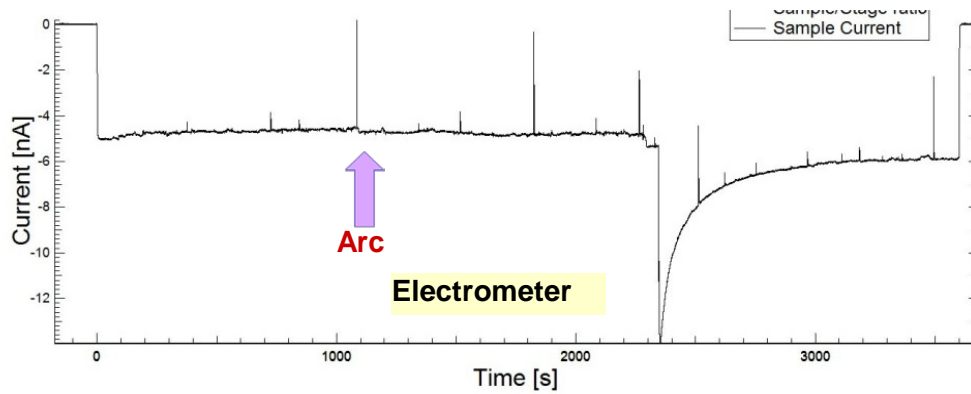
- Carbon-loaded polyimide X0.5 to X0.1 (conductivity)
- Cyanate ester/ graphite fiber X20
- Urethane Epoxy/Carbon fiber X4
- Epoxy/Fiberglass X5

# Varying Intensity Dependence on Incident Energy





# Short Duration Arcs



CCD camera (400nm-900nm) 30 frames/s

## Arc Duration

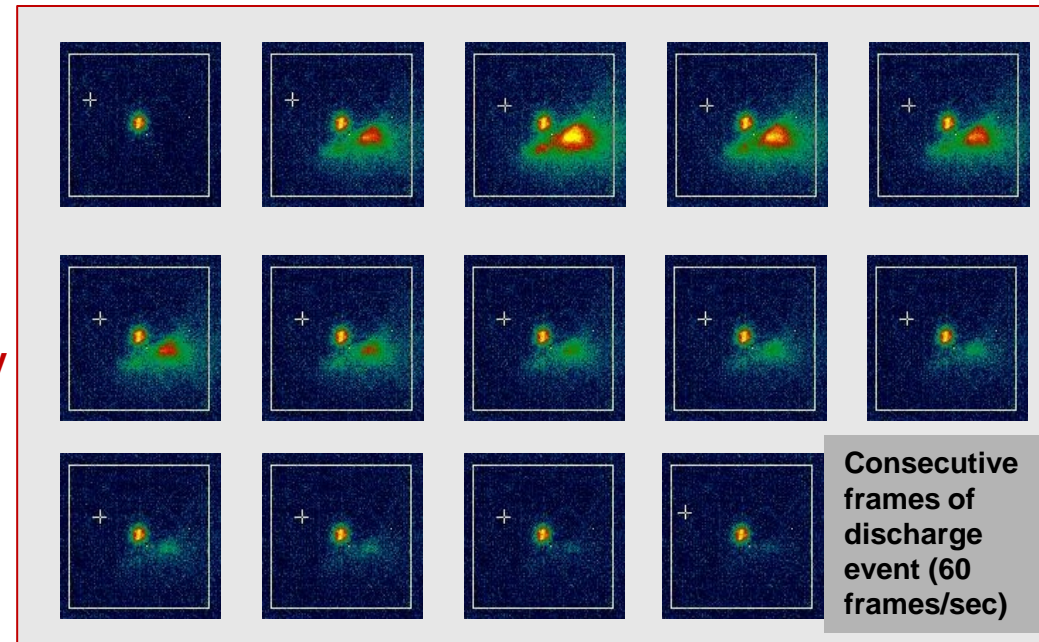
- Abrupt onset
- ~100 ns to ~100 ms exp. decay time
- Seen in electrometers and video cameras

## Arc Frequency

- ~10-100 arcs/hr at ~10 uW/cm<sup>2</sup>
- Rate proportional to current density
- Rate proportional to deposited power
- Varies with material, geometry, conductivity and temperature

## Arc Intensity

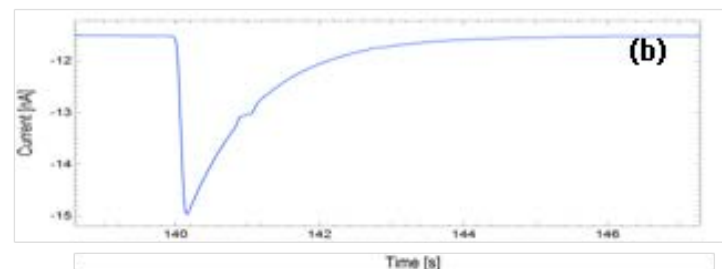
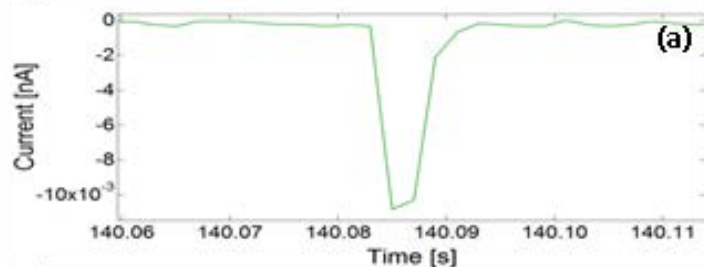
- ~ 10X to 1000X glow amplitude
- ~5% to 20% of glow power
- Seen in radio to UVA  $\lambda$  range
- Optical signature at local point
- Discharge to closest ground



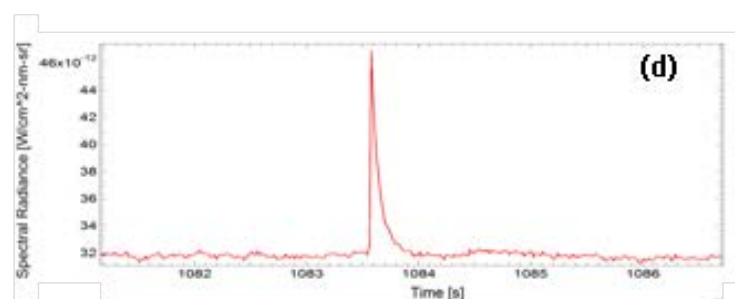
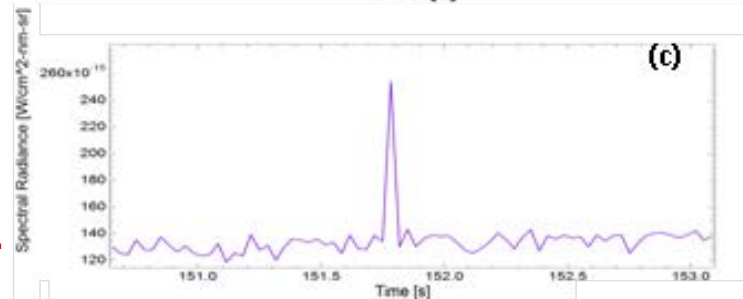
InGaAs camera (900nm-1700nm)

# Short Duration Arcs and Arc Rates

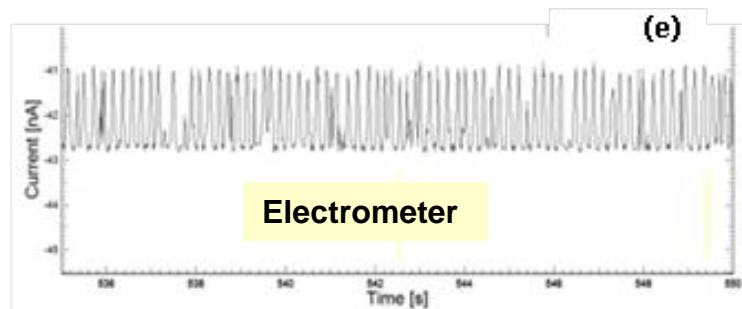
Arc duration in oscilloscopes is often  $\sim 1 \mu\text{s}$ .



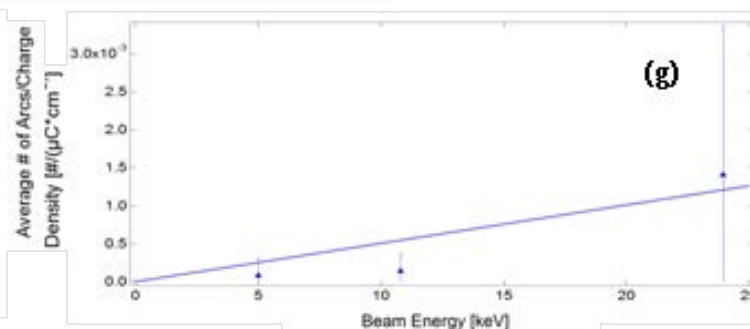
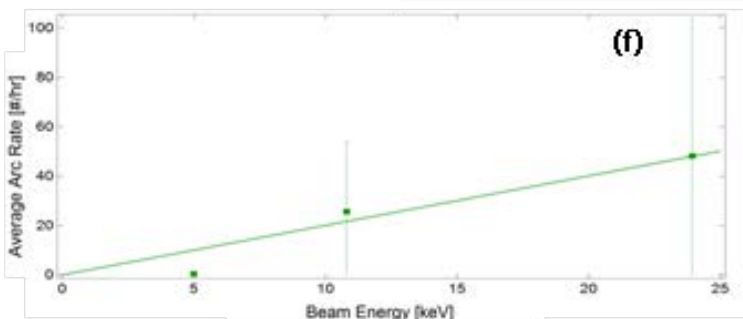
Longer time signatures in electrometer and videos most likely instrumental effect.



Rapid arcing at  $4 \text{ mW/cm}^2$   
 $\sim 20000$  arcs/hr scales with deposited power and charge

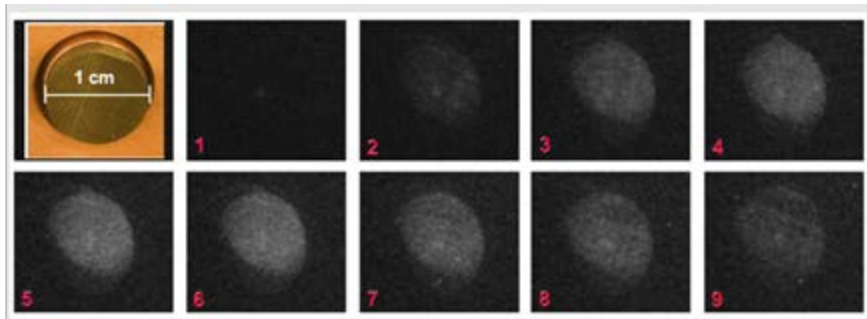


- Rate proportional to current density
- Rate proportional to deposited power
- Rate varies with material, geometry, conductivity and temperature





# Intermediate Duration “Flares”



SLR CCD Camera (400 nm to 900 nm) 30 s/frame

## “Flare” Duration

- Only after ~10 min charging
- Abrupt onset
- ~1-10 min exp. decay time
- Seen in electrometers and video cameras

## “Flare” Frequency

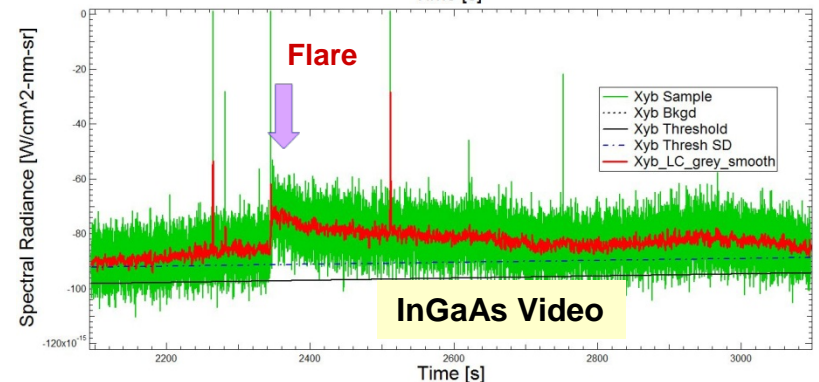
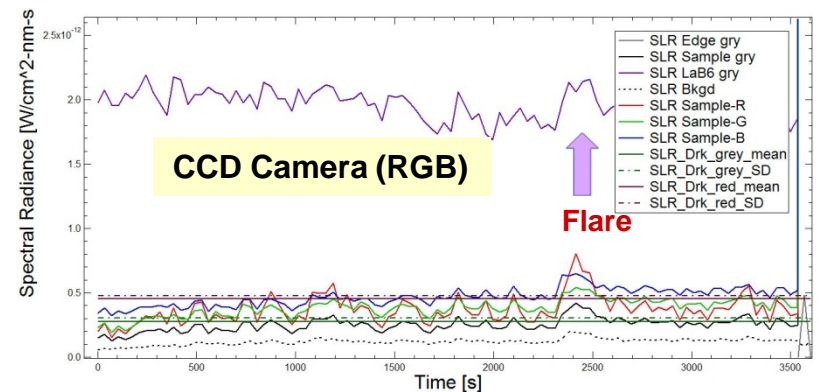
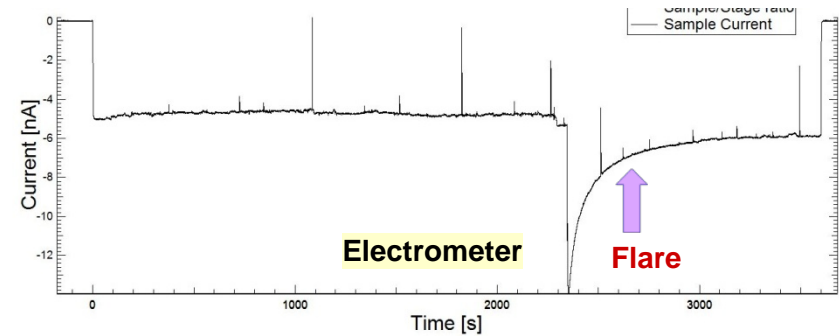
- 0-2 flares/hr

## “Flare” Intensity

- ~ 2X to 20X glow amplitude
- ~5% to 20% of glow power
- Seen in ~300 nm to ~1200 nm range
- Seen over full surface

## “Flare” Properties

- Not seen in glasses
- Origin with large area discharge/charge???



Carbon-loaded Polyimide 22 keV, 5 nA/cm<sup>2</sup>, 110 uW/cm<sup>2</sup>, 135 K

- I. **Space environment electron fluxes produce optical emissions:**
  - **Sustained cathodoluminescence**
  - **Short duration arcs**
  - **Intermediate duration “flares”**
  
- II. **Many dielectric materials produce electron-induced optical emissions.**
  
- III. **Studies conducted for emission dependence on:**
  - **Incident electron energy, current density, power**
  - **Temperature**
  - **Emission wavelength**
  - **Film thickness/range**
  - **Material**
  - **Conductivity**
  
- IV. **Optical emissions can exceed zodiacal background levels in certain conditions**

**Space-based observatory designers should consider space environment electron-induced optical emissions as a potential internal source of stray light.**

**Space observatory conditions enhancing impact of these emissions include:**

- **High flux and high variability environments**
- **High sensitivity imaging**
- **Complex, sensitive optical systems and electronics**
- **Low temperature operations**
- **Large areas**
- **Open architectures**
- **Long, remote missions**

## Disordered SiO<sub>2</sub>

A.E. Jensen, *et al.*, “Properties of Cathodoluminescence for Cryogenic Applications of SiO<sub>2</sub>-based Space Observatory Optics and Coatings,” *SPIE 2013 Paper No.* 8863-11.

JR Dennison, *et al.*, “Electron Beam Induced Luminescence of SiO<sub>2</sub> Optical Coatings,” *IEEE-CEIDP*, 2012.

A. Evans, *et al.*, “Low Temperature Cathodoluminescence of Space Observatory Materials,” *Proc.12<sup>th</sup> Spacecraft Charging Tech. Conf.*, 2012; *IEEE-TPS*, in press.

## Carbon-filed Polyimide

A.E. Jensen, *et al.*, “Nanodielectric Properties of High Conductivity Carbon-Loaded Polyimide Under Electron-Beam Irradiation,” *IEEE-ICSD*, 730-735. 2013.

## Multilayer Dielectric/Conductor Composites

G. Wilson, *et al.*, “Charging Effects of Multilayered Dielectric Spacecraft Materials: Surface Voltage, Discharge and Arcing,” *Proc.12<sup>th</sup> Spacecraft Charging Tech. Conf.*, 2012; *IEEE-TPS*, in press.

## Observation of Emissions

D.C. Ferguson, *et al.*, “On the Feasibility of Detecting Spacecraft Charging and Arcing by Remote Sensing,” *AIAA-ASE*, Paper Number, AIAA-2013-2828, 2013.

## Theory

A.M. Sim and JR Dennison, “Comprehensive Theoretical Framework for Modeling Diverse Electron Transport Experiments in Parallel Plate Geometries,” *AIAA-ASE*, Paper Number, AIAA-2013-2827, 2013.

# Supplemental Slides

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# What Is Different About JWST?

## Extremely Faint Objects

Large sensitive optics

## Large Open Structure

Size and weight constraints

Minimal shielding

Large fluxes

## Observations in IR

Penetration through intergalactic dust clouds

Optimized for (0.6 – 28  $\mu\text{m}$ )

## Very Low Temperature

Passive cooling

Virtually all insulators go to infinite resistance—perfect charge integrators

## Large Sunshield

Large areas

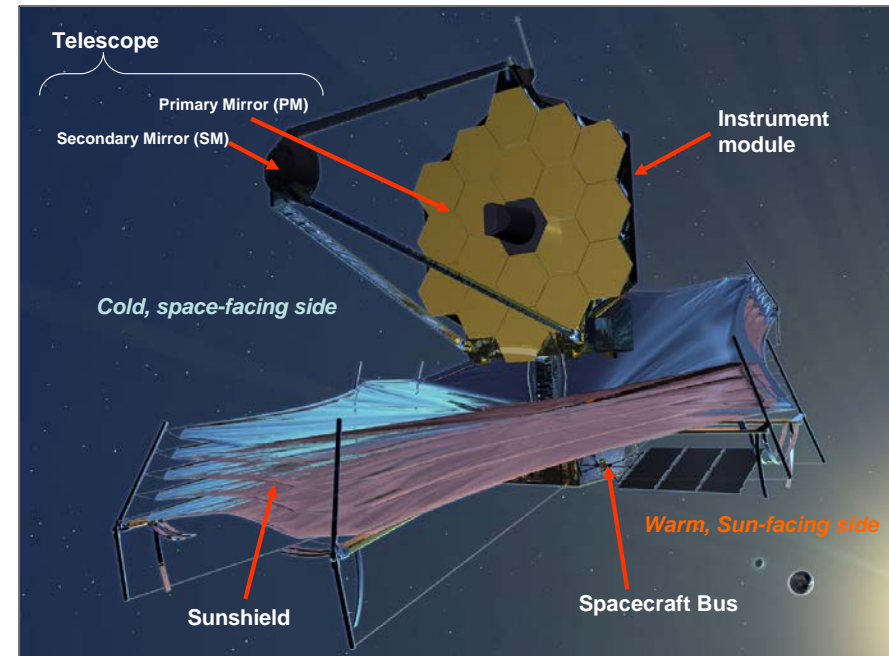
Constant eclipse with no photoemission

## Stable, Low Light Environment

Orbit at L2

Large solar activity variations

In and out of magnetotail



## Long Mission Lifetime (10-20 yr)

No repairs

Very long integration times

## Complex, Sensitive Hardware

Large sensitive optics

Complex, cold electronics

## Paradigm Shift in Design Methods

To big for conventional ground tests



## JWST

Sunshield  
Space  
Passive Cooling  
Light Flux  
Charge Flux  
Low Flux  
Mission Lifetime  
(~20 yr)

## USU Lab

Small Test Samples (~1 cm<sup>2</sup>)  
UHV Chamber (~10<sup>-9</sup> Torr)  
Cryo Cooling (>30 K)  
No Light (dark room & chamber)  
Monoenergetic e-Beam (20eV to 30keV)  
Low Flux (<0.05 nA/cm<sup>2</sup> to >500 nA/cm<sup>2</sup>)  
**Fountain of Youth and Pot of Au**  
➔ Accelerated Testing

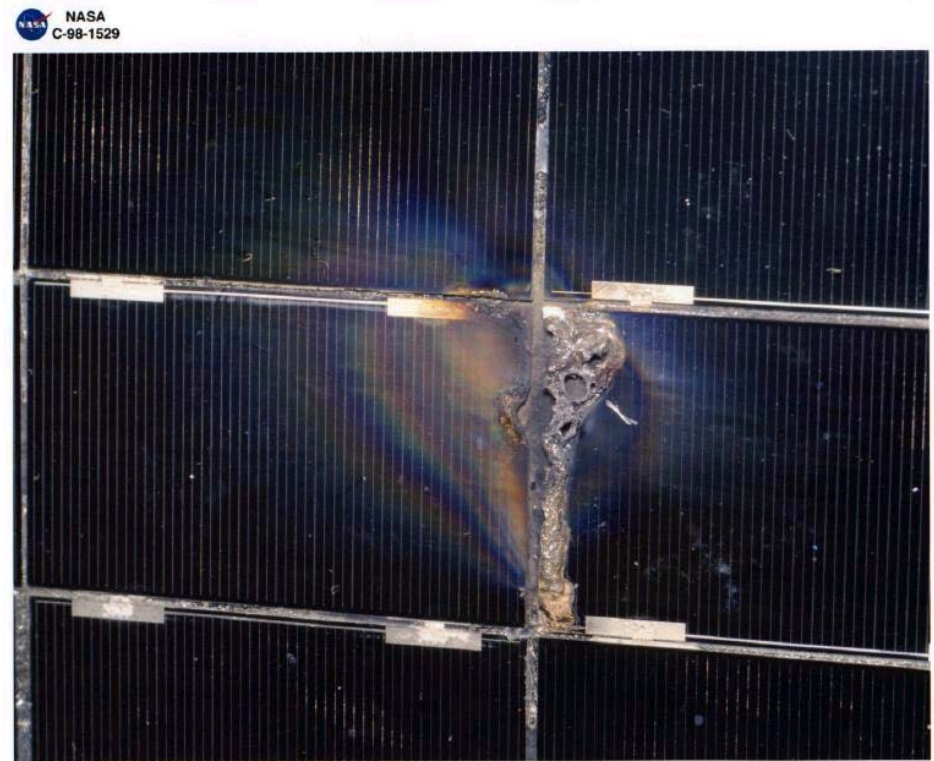
# Primary Motivation For Our Research—Spacecraft Charging

NASA's concern for spacecraft charging is caused by plasma environment electron, ion, and photon-induced currents.

**Charging can cause performance degradation or complete failure.**

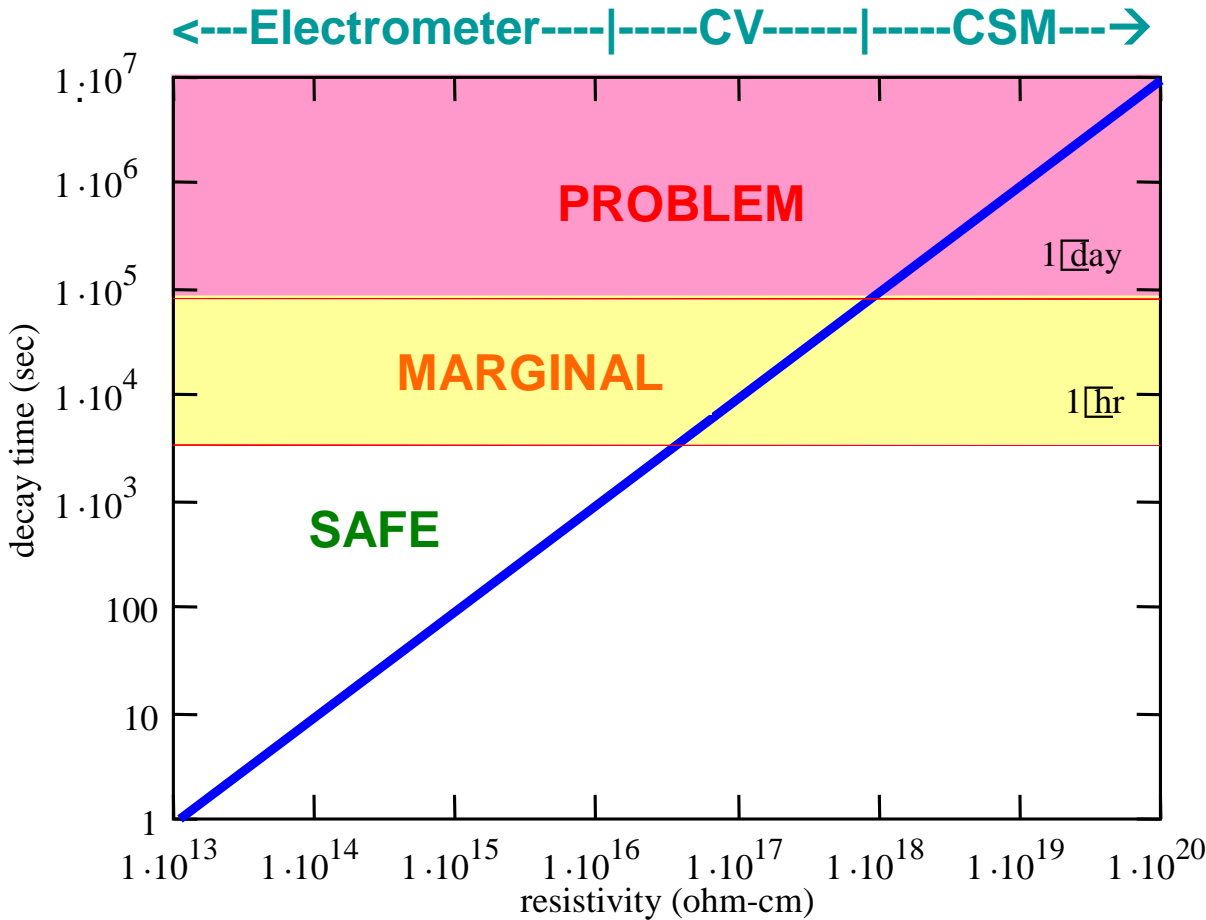
**Majority of all spacecraft failures and anomalies due to the space environment result from plasma-induced charging**

- *Single event interrupts of electronics*
- *Arching*
- *Sputtering*
- *Enhanced contamination*
- *Shifts in spacecraft potentials*
- *Current losses*



Solar panel damaged by localized charging event

# Critical Time Scales and Resistivities



## Range of Charge Storage Method

1 min  $\rightarrow \rho \cdot \epsilon_0 \sim 1 \cdot 10^{15} \Omega\text{-cm}$

1 hr  $\rightarrow \rho \cdot \epsilon_0 \sim 4 \cdot 10^{16} \Omega\text{-cm}$

1 day  $\rightarrow \rho \cdot \epsilon_0 \sim 1 \cdot 10^{18} \Omega\text{-cm}$

1 yr  $\rightarrow \rho \cdot \epsilon_0 \sim 4 \cdot 10^{20} \Omega\text{-cm}$

10 yr  $\rightarrow \rho \cdot \epsilon_0 \sim 4 \cdot 10^{21} \Omega\text{-cm}$

-----  
500 yr  $\rightarrow \rho \cdot \epsilon_0 \sim 1 \cdot 10^{23} \Omega\text{-cm}$

Decay time vs. resistivity base on simple capacitor model.

$$\tau = \rho \epsilon_r \epsilon_0$$

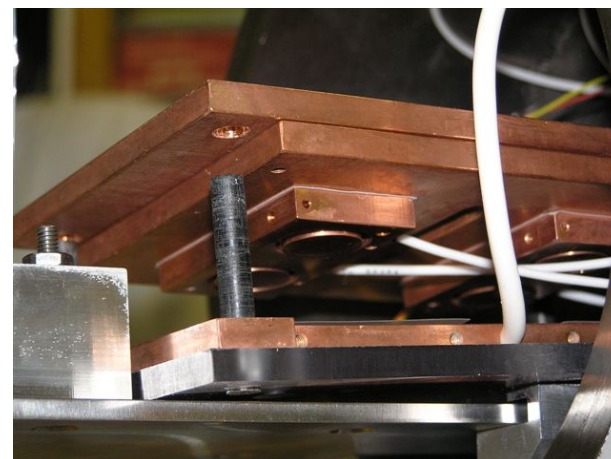
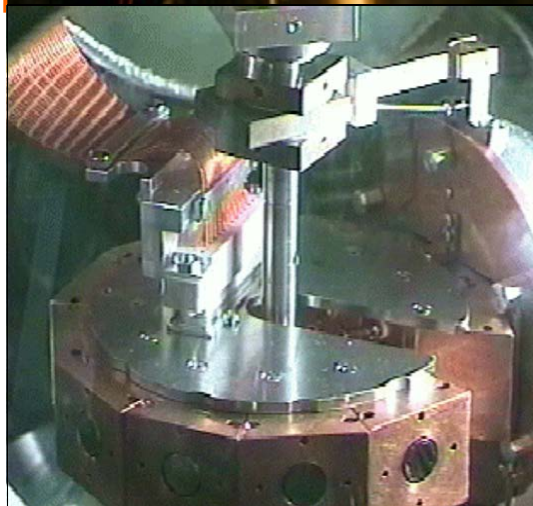
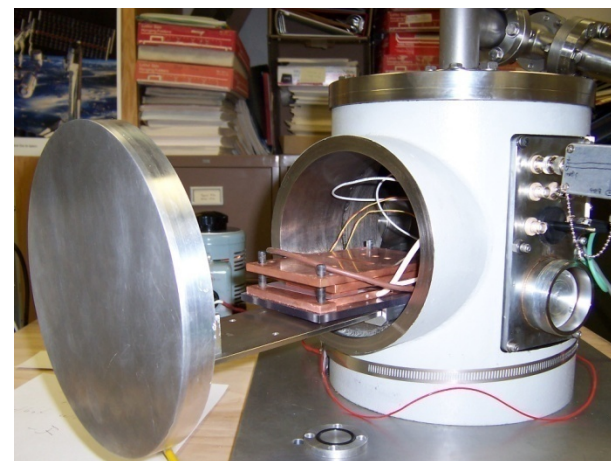
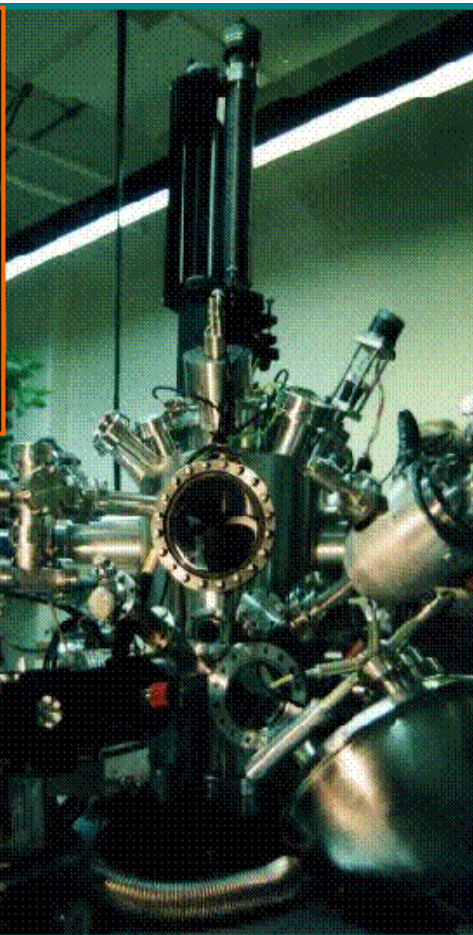
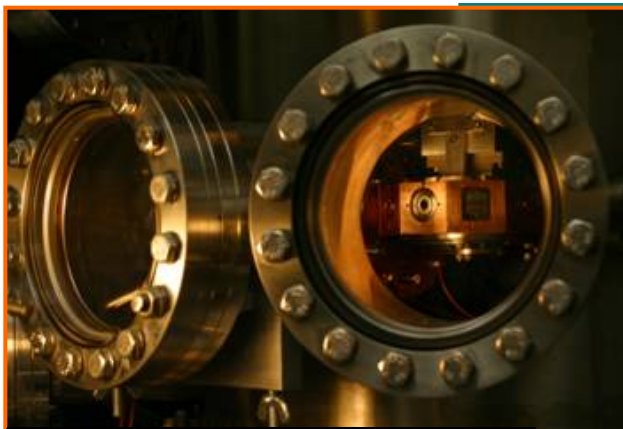
# Materials Physics Group Measurement Capabilities

Electron Emission  
Ion Yield

Photoyield  
Luminescence

Conductivity  
Electrostatic Discharge

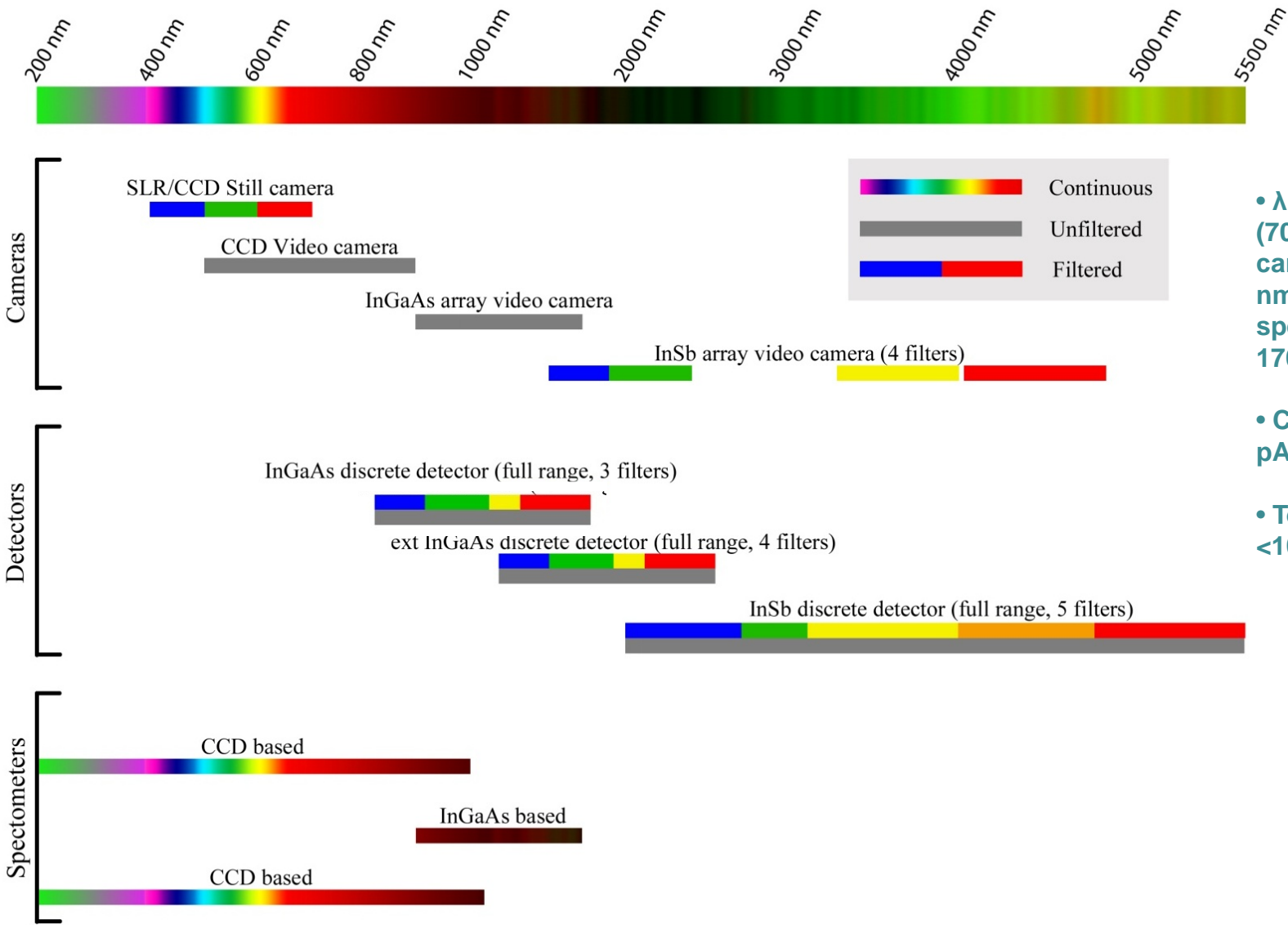
Radiation Induced Cond.  
Radiation Damage



Dependence on: Press., Temp., Charge, E-field, Dose, Dose Rate



# USU Phase V-A Arc/Glow Instrumentation Ranges



- $\lambda$  range: detectors (700-5500 nm), cameras (400-5000 nm), and spectrometers (200-1700 nm)

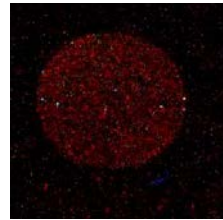
- Current range: (0.1 pA to 1 mA)

- Temporal range:  $<10^{-9}$  s to  $>10^4$  s

# Electron-Induced Luminescence

## USU Tests

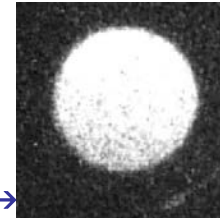
1 cm Dia test samples  
30 s Exposure SLR  
Camera



Kapton XC

500 nA/cm<sup>2</sup>  
22 keV  
150 K

← SLR NIR Video 33 ms exp. →



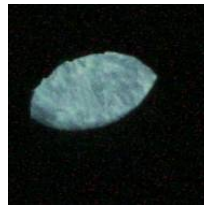
“Flare”

M55J

1 nA/cm<sup>2</sup>  
22 keV  
100 K



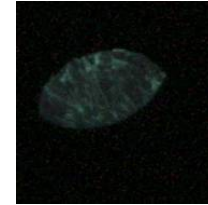
Sustained Glow



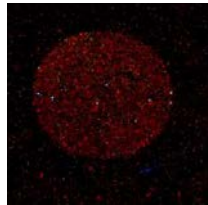
“Flare”

IEC Shell Face Epoxy  
Resin with Carbon Veil

1 nA/cm<sup>2</sup>  
22 keV  
100 K

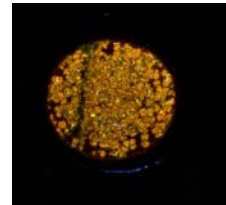


Sustained Glow



Sustained Glow

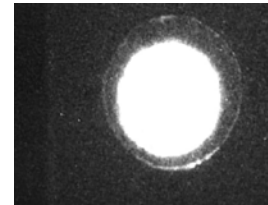
1 nA/cm<sup>2</sup>  
22 keV  
100 K  
100 s exp.



Sustained Glow

Kapton E

500 nA/cm<sup>2</sup>  
22 keV  
150 K



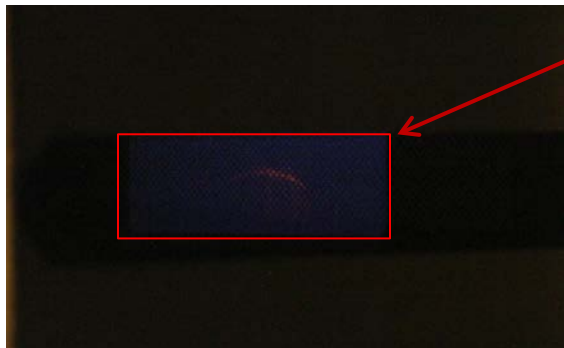
NIR Video

5 uA/cm<sup>2</sup>  
22 keV  
150 K



Sample Area

Surface Glow  
296 K



Surface Glow  
294 K



Surface Glow  
90 K



Surface Glow  
130 K



## T300 Glow seen at MSFC

Flux density = 1 nA/cm<sup>2</sup>

Energy = 22 keV

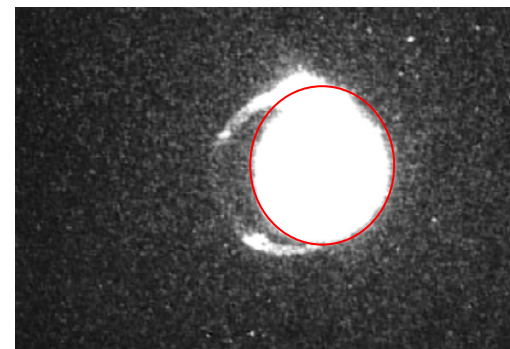
Power 22 uW/cm<sup>2</sup>

Temp = 296 K and 90 K

$$I_{90}/I_{296} \sim 4$$

Similar behavior seen for M55J  
and Black Kapton

“Flare”  
130 K



## M55J Glow seen at USU

Flux density = 5 nA/cm<sup>2</sup>

Energy = 22 keV

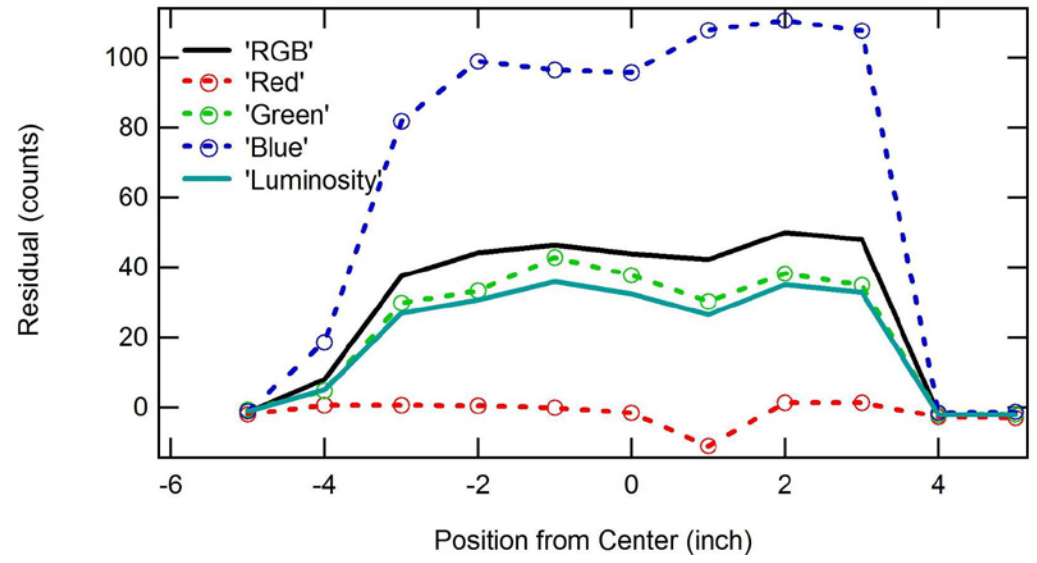
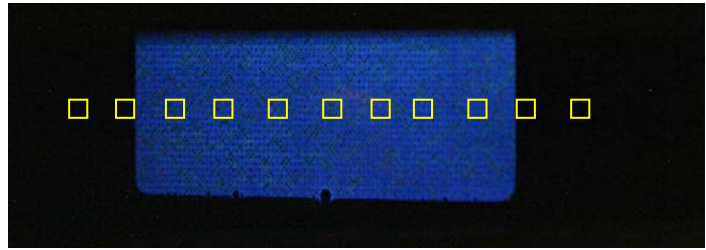
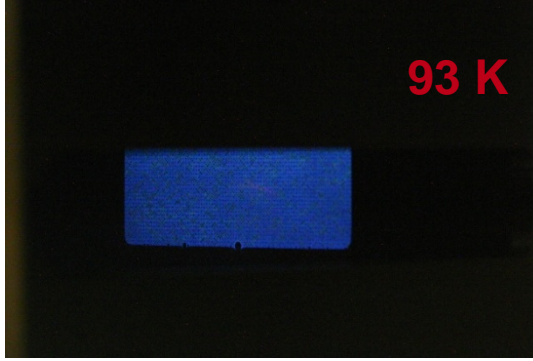
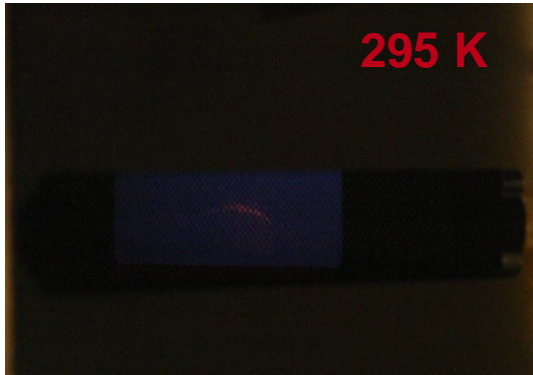
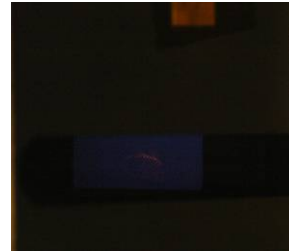
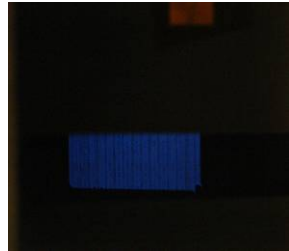
Power 110 uW/cm<sup>2</sup>

Temp = 294 K and 130 K

## MSFC Tests

15x5 cm test samples  
120 s Exp. SLR Camera

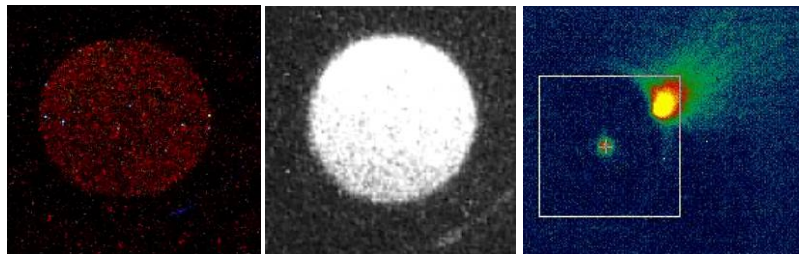
M55J	T300 DTA
1 nA/cm <sup>2</sup>	1 nA/cm <sup>2</sup>
22 keV	22 keV
90 K	90 K



## Primary Concern:

What are the risks related to spacecraft charging—including arcing and electron-induced luminescence—for insulating structural materials and mirrors or other optical surfaces when exposed to electron fluxes under “worst case storm” or prolonged typical L2 conditions?

Black Kapton XC Blanket



Surface Glow

“Flare”

Arc

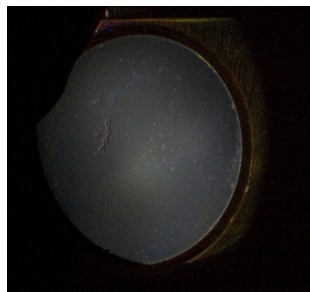
M55J Carbon/Epoxy Composite



Surface Glow

“Flare”

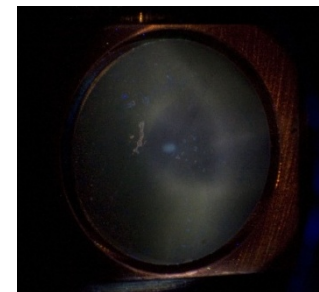
Arc and “Flare”

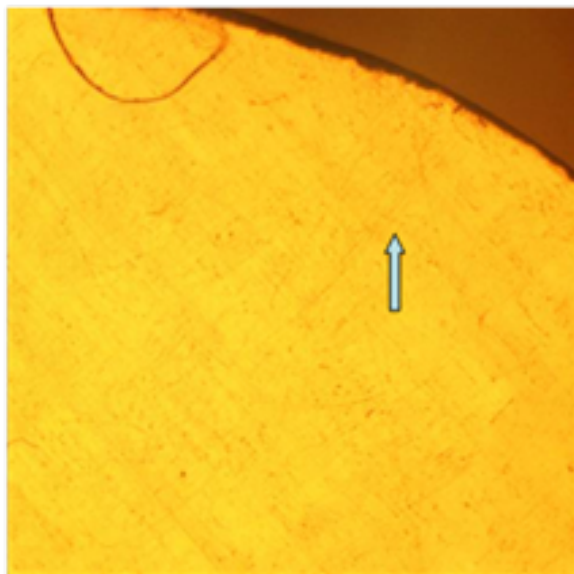


Disordered SiO<sub>2</sub> Optical Coatings on Mirrors

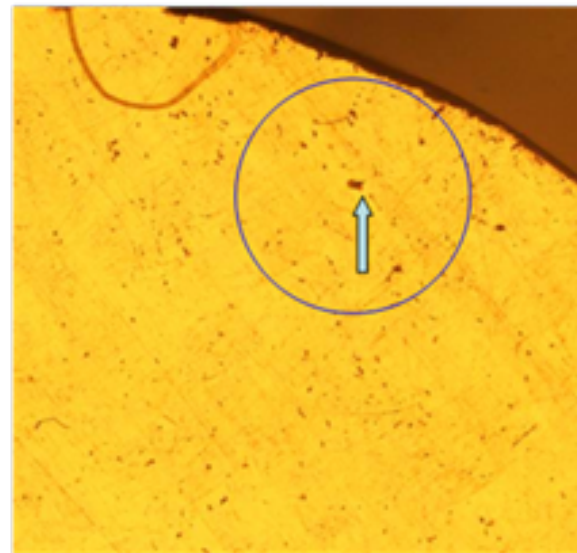
**Play movie**  
**POMGlow.wmv**

Surface Glow





(a)

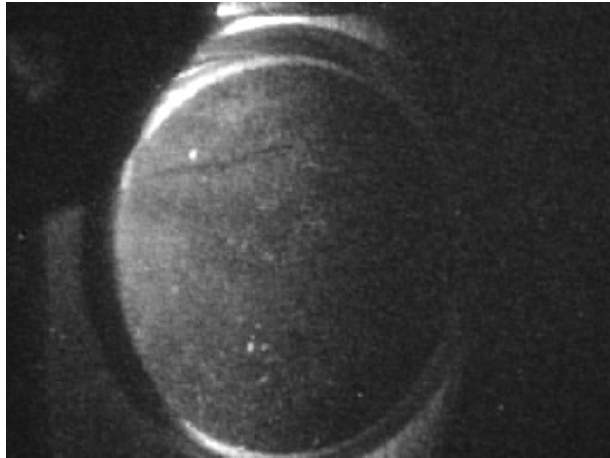


(b)

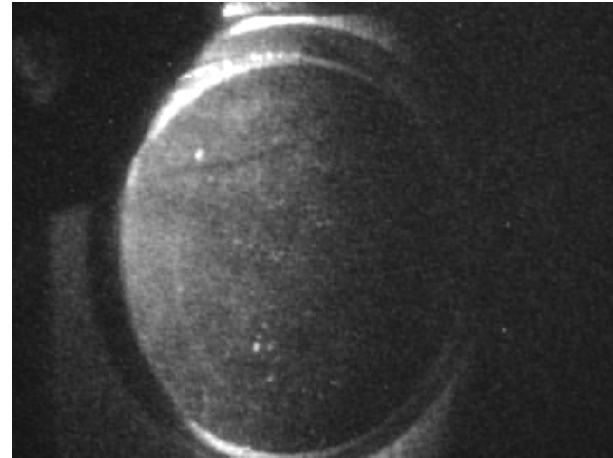
Figure 8. Comparison of optical microscope images of composite sample surface (a) before and (b) after electron bombardment ( $22 \mu\text{W}/\text{cm}^2$ ,  $1 \text{ nA}/\text{cm}^2$  at  $22 \text{ keV}$ ) at  $150 \text{ K}$ . Sample is a composite material with an ungrounded  $0.1 \mu\text{m}$  Au/Cr coating on an epoxy resin fiberglass and carbon fiber composite substrate, with the Au side exposed to beam. Numerous damage sites from arcing are evident on the exposed sample, including the  $\sim 250 \mu\text{m}$  diameter features identified with the arrow.



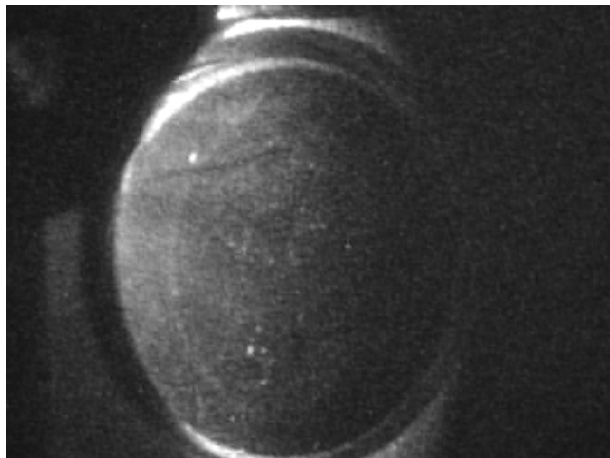
# Example of POM Arc-Video



Frame before  
arc



Frame of  
arc



Frame after arc



Difference between frame before  
and frame of arc